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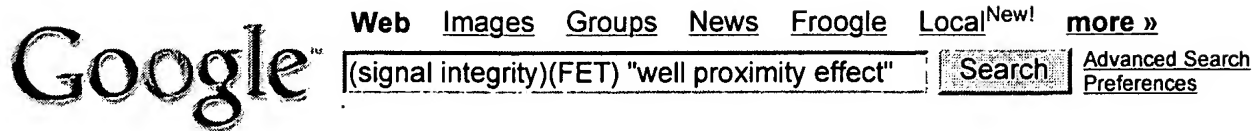
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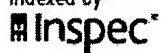
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- ☐ 1. **Very low threshold oxide-confined 1.3 μ m GaAs-based quantum dot laser**
 Park, G.; Shchekin, O.B.; Huffaker, D.L.; Deppe, D.G.;
 Lasers and Electro-Optics, 2000. (CLEO 2000). Conference on
 7-12 May 2000 Page(s):349 - 350
 Digital Object Identifier 10.1109/CLEO.2000.907100
[AbstractPlus](#) | Full Text: [PDF](#)(168 KB) IEEE CNF
- ☐ 2. **Reduced threshold vertical-cavity surface-emitting lasers**
 Young, D.B.; Kapila, A.; Scott, J.W.; Malhotra, V.; Coldren, L.A.;
 Electronics Letters
 Volume 30, Issue 3, 3 Feb. 1994 Page(s):233 - 235
[AbstractPlus](#) | Full Text: [PDF](#)(256 KB) IEE JNL
- ☐ 3. **Multi-quantum well GaInNAs/GaAs lasers with low threshold current den:
 MOCVD**
 Cheng, J.; Li, N.Y.; Hains, C.P.; Yang, K.;
 Device Research Conference Digest, 1999 57th Annual
 28-30 June 1999 Page(s):192 - 193
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- ☐ 1. CMOS Vt-control improvement through implant lateral scatter elimination
Polishchuk, I.; Mathur, N.; Sandstrom, C.; Manos, P.; Pohland, O.;
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13-15 Sept. 2005 Page(s):193 - 196
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